



## CD74HC4051-EP Analog Multiplexer and Demultiplexer

### 1 Features

- Controlled Baseline
  - One Assembly and Test Site, One Fabrication Site
- Extended Temperature Performance of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product Change Notification
- Qualification Pedigree<sup>(1)</sup>
- Wide Analog Input Voltage Range of  $\pm 5\text{ V}$  Max
- Low ON-Resistance
  - $70\ \Omega$  Typical ( $V_{\text{CC}} - V_{\text{EE}} = 4.5\text{ V}$ )
  - $40\ \Omega$  Typical ( $V_{\text{CC}} - V_{\text{EE}} = 9\text{ V}$ )
- Low Crosstalk Between Switches
- Fast Switching and Propagation Speeds
- Break-Before-Make Switching
- Operation Control Voltage =  $2\text{ V}$  to  $6\text{ V}$
- Switch Voltage =  $0\text{ V}$  to  $10\text{ V}$
- High Noise Immunity  $N_{\text{IL}} = 30\%$ ,  $N_{\text{IH}} = 30\%$  of  $V_{\text{CC}}$ ,  $V_{\text{CC}} = 5\text{ V}$  <sup>(1)</sup>

### 2 Applications

Supports Defense and Aerospace Applications

- (1) Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

### 3 Description

The CD74HC4051-EP is a digitally controlled analog switch that uses silicon gate CMOS technology to achieve operating speeds similar to LSTTL, with the low power consumption of standard CMOS integrated circuits.

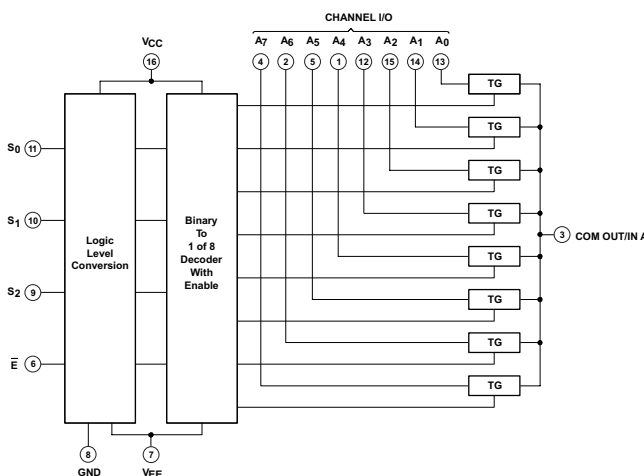
This analog multiplexer and demultiplexer controls analog voltages that may vary across the voltage supply range (that is,  $V_{\text{CC}}$  to  $V_{\text{EE}}$ ). These bidirectional switches allow the use of any analog input as an output and vice versa. The switches have low ON-resistance and low OFF leakages. In addition, the device has an enable control (E) that, when high, disables all switches to their OFF state.

#### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)
CD74HC4051-EP	SOIC (16)	4.00 mm x 10.00 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

#### Functional Block Diagram



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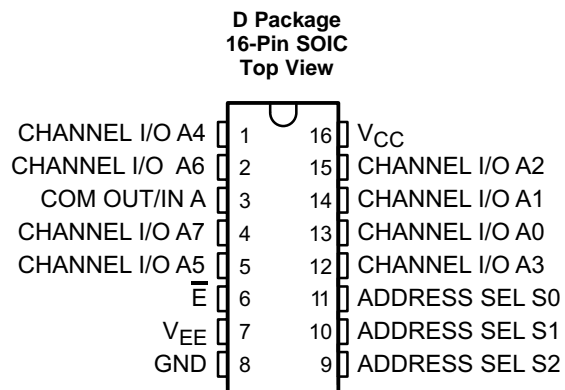
## 4 Revision History

### Changes from Original (September 2002) to Revision A

Page

- Added *ESD Ratings* table, *Feature Description* section, *Device Functional Modes*, *Application and Implementation* section, *Power Supply Recommendations* section, *Layout* section, *Device and Documentation Support* section, and *Mechanical, Packaging, and Orderable Information* section. .... **1**

## 5 Pin Configuration And Functions



**Pin Functions**

PIN		I/O	DESCRIPTION
NAME	NO.		
A4	1	I/O	Channel 4 input / output
A6	2	I/O	Channel 6 Input / output
A	3	I/O	COM OUT/ IN
A7	4	I/O	Channel 7 Input / Output
A5	5	I/O	Channel 5 Input / Output
Ebar	6	I	Enable input
VEE	7	I	Power input level for incoming Channel
GND	8	I	Power GND
VCC	9	I	Power input level for outgoing Channel
A2	10	I/O	Channel 2 Input / Output
A1	11	I/O	Channel 1 Input / Output
A0	12	I/O	Channel 0 Input / Output
A3	13	I/O	Channel 3 Input / Output
S0	14	I	Address Select Input 0
S1	15	I	Address Select Input 1
S2	15	I	Address Select Input 2

## 6 Specifications

### 6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) <sup>(1)</sup>

		MIN	MAX	UNIT
$V_{CC} - V_{EE}^{(2)}$	Supply voltage	–0.5	10.5	V
$V_{CC}$		–0.5	7	
$V_{EE}$		0.5	–7	
$I_{IK}$	Input clamp current ( $V_I < -0.5$ V or $V_I > V_{CC} + 0.5$ V)	–20	20	mA
$I_{OK}$	Output clamp current ( $V_O < V_{EE} - 0.5$ V or $V_O > V_{CC} + 0.5$ V)	–20	20	mA
	Switch current ( $V_I > V_{EE} - 0.5$ V or $V_I < V_{CC} + 0.5$ V)	–25	25	mA
	Continuous current through $V_{CC}$ or GND	–50	50	mA
$I_{EE}$	$V_{EE}$ current	0	20	mA
$\theta_{JA}$	Package thermal impedance <sup>(3)</sup>		73	°C/W
$T_J$	Maximum junction temperature		150	°C
$T_{stg}$	Storage temperature	–65	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages referenced to GND unless otherwise specified.
- (3) The package thermal impedance is calculated in accordance with JESD 51-7.

### 6.2 ESD Ratings

		VALUE	UNIT
$V_{(ESD)}$ Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins <sup>(1)</sup>	±2000	V
	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins <sup>(2)</sup>	±500	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

### 6.3 Recommended Operating Conditions<sup>(1)</sup>

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
$V_{CC}$	Supply voltage <sup>(2)</sup>	2	6	6	V
	Supply voltage, $V_{CC} - V_{EE}$ (see <a href="#">Figure 4</a> )	2	10	10	V
$V_{EE}$	Supply voltage, (see <sup>(2)</sup> and <a href="#">Figure 5</a> )	0	–6	–6	V
$V_{IH}$	High-level input voltage	$V_{CC} = 2$ V	1.5		V
		$V_{CC} = 4.5$ V	3.15		
		$V_{CC} = 6$ V	4.2		
$V_{IL}$	Low-level input voltage	$V_{CC} = 2$ V		0.5	V
		$V_{CC} = 4.5$ V		1.35	
		$V_{CC} = 6$ V		1.8	
$V_I$	Input control voltage	0		$V_{CC}$	V
$V_{IS}$	Analog switch I/O voltage	$V_{EE}$		$V_{CC}$	V
$t_t$	Input transition (rise and fall) time	$V_{CC} = 2$ V	0	1000	ns
		$V_{CC} = 4.5$ V	0	500	
		$V_{CC} = 6$ V	0	400	

- (1) All unused inputs of the device must be held at  $V_{CC}$  or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, [SCBA004](#).
- (2) In certain applications, the external load resistor current may include both  $V_{CC}$  and signal-line components. To avoid drawing  $V_{CC}$  current when switch current flows into the transmission gate inputs, the voltage drop across the bidirectional switch must not exceed 0.6 V (calculated from  $r_{on}$  values shown in [Electrical Characteristics](#) table). No  $V_{CC}$  current flows through  $R_L$  if the switch current flows into the COM OUT/IN A terminal.

## Recommended Operating Conditions<sup>(1)</sup> (continued)

over operating free-air temperature range (unless otherwise noted)

	MIN	NOM	MAX	UNIT
$T_A$ Operating free-air temperature	–55		125	°C
$C_{pd}$ Power dissipation capacitance <sup>(3)</sup>		50		pF

(3)  $C_{pd}$  is used to determine the dynamic power consumption, per package.

$$P_D = C_{pd} V_{CC}^2 f_I + \sum (C_L + C_S) V_{CC}^2 f_O$$

$f_O$  = output frequency

$f_I$  = input frequency

$C_L$  = output load capacitance

$C_S$  = switch capacitance

$V_{CC}$  = supply voltage

## 6.4 Thermal Information

THERMAL METRIC <sup>(1)</sup>		CD74HC4051-EP	UNIT
		D (SOIC)	
		16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	81.7	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	43.1	
$R_{\theta JB}$	Junction-to-board thermal resistance	39.2	
$\Psi_{JT}$	Junction-to-top characterization parameter	10.7	
$\Psi_{JB}$	Junction-to-board characterization parameter	38.9	

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, [SPRA953](#).

## 6.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V <sub>EE</sub>	V <sub>CC</sub>	T <sub>A</sub> = 25°C		T <sub>A</sub> = −55°C to 125°C			UNIT
					MIN	TYP	MAX	MIN	TYP	
r <sub>on</sub>	I <sub>O</sub> = 1 mA, V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub> . See <a href="#">Figure 1</a>	V <sub>IS</sub> = V <sub>CC</sub> or V <sub>EE</sub>	0 V	4.5 V	70	160	240			Ω
			0 V	6 V	60	140	210			
			−4.5 V	4.5 V	40	120	180			
		V <sub>IS</sub> = V <sub>CC</sub> to V <sub>EE</sub>	0 V	4.5 V	90	180	270			
			0 V	6 V	80	160	240			
			−4.5 V	4.5 V	45	130	195			
Δr <sub>on</sub>	Between any two channels	0 V	4.5 V	10				Ω		
		0 V	6 V	8.5						
		−4.5 V	4.5 V	5						
I <sub>IZ</sub>	For switch OFF: When V <sub>IS</sub> = V <sub>CC</sub> , V <sub>OS</sub> = V <sub>EE</sub> ; When V <sub>IS</sub> = V <sub>EE</sub> , V <sub>OS</sub> = V <sub>CC</sub> For switch ON: All applicable combinations of V <sub>IS</sub> and V <sub>OS</sub> voltage levels, V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	0 V	6 V	±0.2		±2			μA	
		−5 V	5 V	±0.4		±4				
I <sub>IL</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND		0 V	6 V	±0.1		±1			μA
I <sub>CC</sub>	I <sub>O</sub> = 0, V <sub>I</sub> = V <sub>CC</sub> or GND	When V <sub>IS</sub> = V <sub>EE</sub> , V <sub>OS</sub> = V <sub>CC</sub>	0 V	6 V	8		160			μA
		When V <sub>IS</sub> = V <sub>CC</sub> , V <sub>OS</sub> = V <sub>FF</sub>	−5 V	5 V	16		320			

## 6.6 Analog Channel Characteristics

 $T_A = 25^\circ\text{C}$ 

PARAMETER	TEST CONDITIONS	$V_{EE}$	$V_{CC}$	MIN	TYP	MAX	UNIT
$C_I$ Switch input capacitance					5		pF
$C_{COM}$ Common output capacitance					25		pF
$f_{max}$ Minimum switch frequency response at –3 dB	See <a href="#">Figure 6</a> , <a href="#">Figure 2</a> , and <sup>(1)(2)</sup>	–2.25 V	2.25 V		145		MHz
		–4.5 V	4.5 V		180		
Sine-wave distortion	See <a href="#">Figure 7</a>	–2.25 V	2.25 V		0.03%		
		–4.5 V	4.5 V		0.018%		
Switch OFF signal feedthrough	See <a href="#">Figure 8</a> , <a href="#">Figure 3</a> and <sup>(2)(3)</sup>	–2.25 V	2.25 V		–73		dB
		–4.5 V	4.5 V		–75		

(1) Adjust input voltage to obtain 0 dBm at  $V_{OS}$  for  $f_{IN} = 1$  MHz.

(2)  $V_{IS}$  is centered at  $(V_{CC} - V_{EE})/2$ .

(3) Adjust input for 0 dBm

## 6.7 Switching Characteristics

over recommended operating free-air temperature range (unless otherwise noted) (see [Figure 9](#))

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	V <sub>EE</sub>	V <sub>CC</sub>	T <sub>A</sub> = 25°C			T <sub>A</sub> = −55°C TO 125°C			UNIT
						MIN	TYP	MAX	MIN	TYP	MAX	
t <sub>pd</sub>	IN	OUT	C <sub>L</sub> = 15 pF		5 V			4				ns
			C <sub>L</sub> = 50 pF	0 V	2 V			60			90	
					4.5 V			12			18	
					6 V			10			15	
					−4.5 V	4.5 V		8			12	
C <sub>L</sub> = 15 pF		5 V			19						ns	
t <sub>en</sub>	ADDRESS SEL or E	OUT	C <sub>L</sub> = 50 pF	0 V	2 V			225				340
					4.5 V			45				68
					6 V			38				57
					−4.5 V	4.5 V		32				48
t <sub>dis</sub>	ADDRESS SEL or E	OUT	C <sub>L</sub> = 15 pF		5 V			19				ns
			C <sub>L</sub> = 50 pF	0 V	2 V			225			340	
					4.5 V			45			68	
					6 V			38			57	
					−4.5 V	4.5 V		32			48	
C <sub>I</sub>	Control		C <sub>L</sub> = 50 pF					10			10	pF

## 6.8 Typical Characteristics

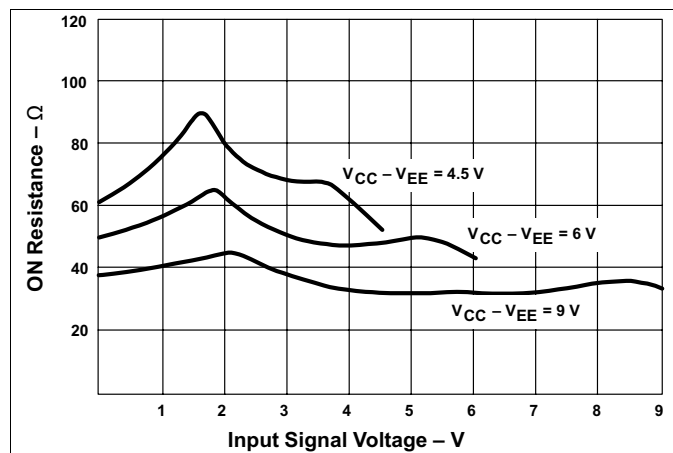


Figure 1. Typical ON-Resistance vs Input Signal Voltage

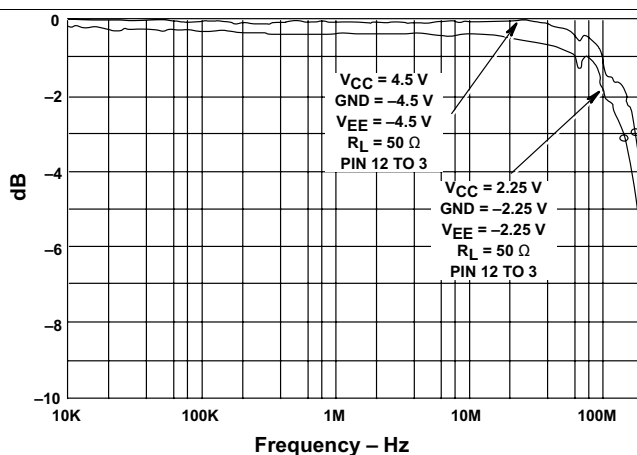


Figure 2. Channel On Bandwidth

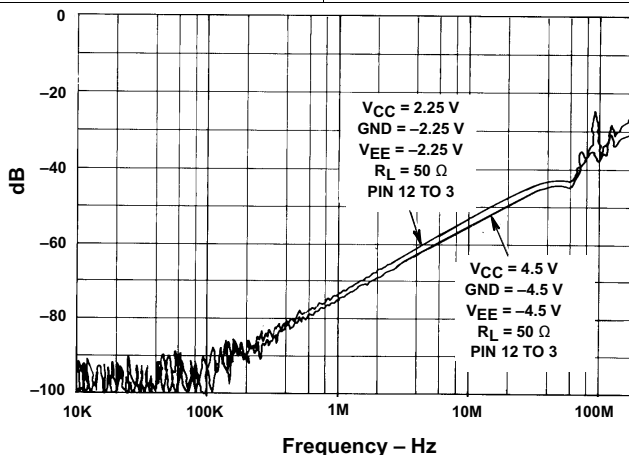


Figure 3. Channel Off Feedthrough

### 6.8.1 Recommended Operating Area as a Function of Supply Voltages

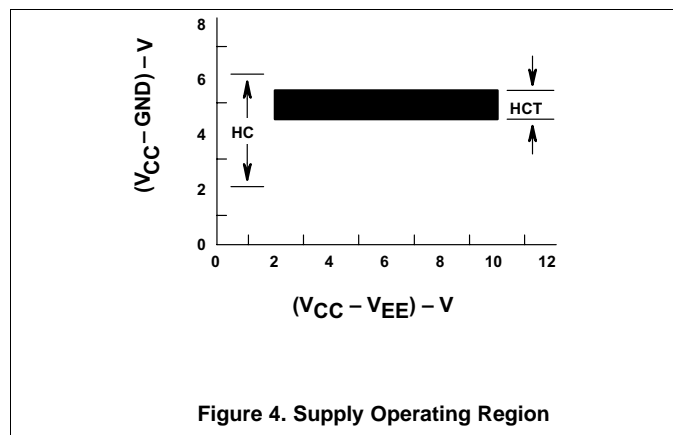


Figure 4. Supply Operating Region

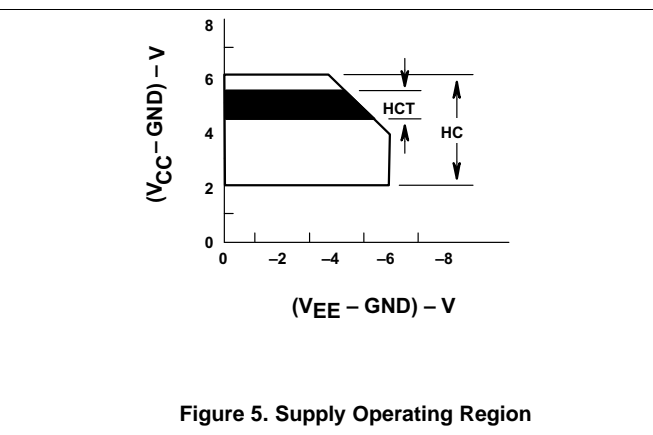
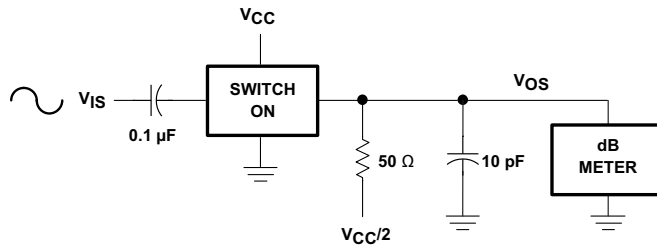
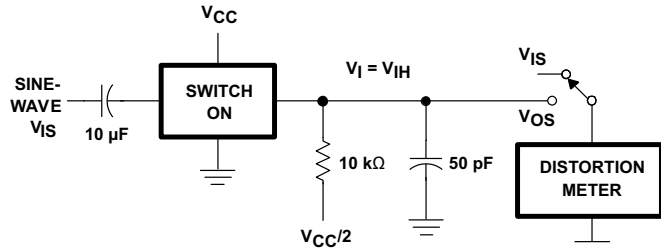


Figure 5. Supply Operating Region

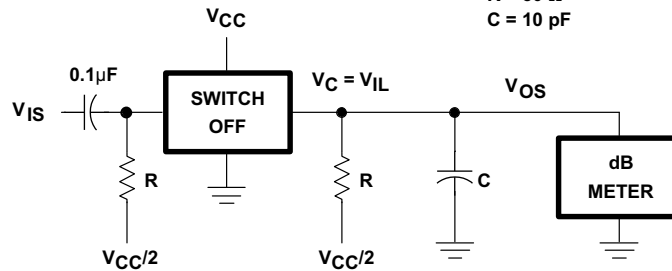
## 7 Parameter Measurement Information



**Figure 6. Frequency-Response Test Circuit**



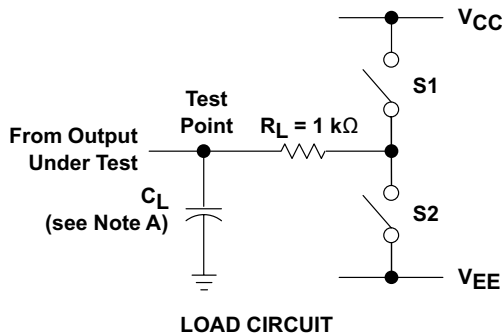
**Figure 7. Sine-Wave Distortion Test Circuit**

 $f_{IS} \geq 1\text{-MHz SINE WAVE}$ 
 $R = 50\ \Omega$ 
 $C = 10\ \text{pF}$ 


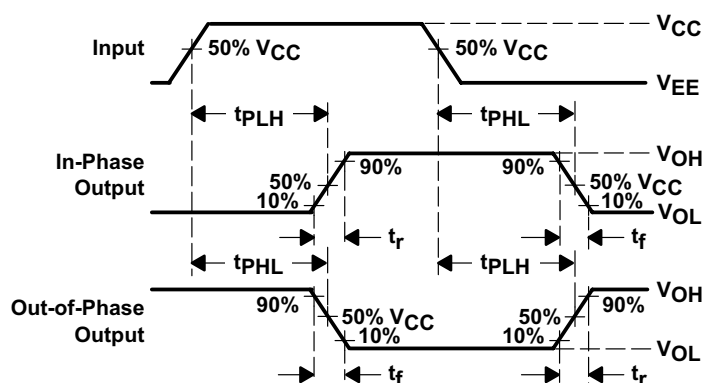
**Figure 8. Switch OFF Signal Feedthrough Test Circuit**



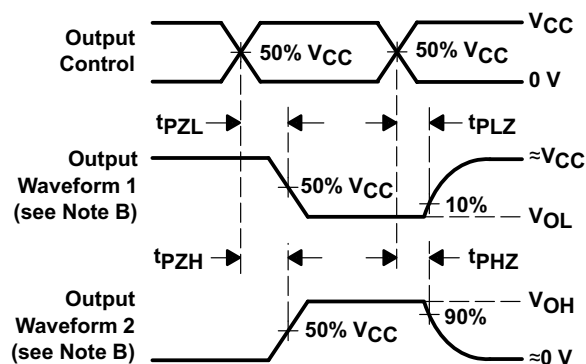
## Parameter Measurement Information (continued)



PARAMETER		S1	S2
$t_{en}$	$tpZH$	Open	Closed
	$tpZL$	Closed	Open
$t_{dis}$	$tpHZ$	Open	Closed
	$tpLZ$	Closed	Open
$t_{pd}$		Open	Open



**VOLTAGE WAVEFORMS  
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES**



**VOLTAGE WAVEFORMS  
OUTPUT ENABLE AND DISABLE TIMES**

- NOTES: A.  $C_L$  includes probe and test-fixture capacitance.  
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
 C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 1$  MHz,  $Z_O = 50 \Omega$ ,  $t_r = 6$  ns,  $t_f = 6$  ns.  
 D. For clock inputs,  $f_{max}$  is measured with the input duty cycle at 50%.  
 E. The outputs are measured one at a time with one input transition per measurement.  
 F.  $tpLZ$  and  $tpHZ$  are the same as  $t_{dis}$ .  
 G.  $tpZL$  and  $tpZH$  are the same as  $t_{en}$ .  
 H.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

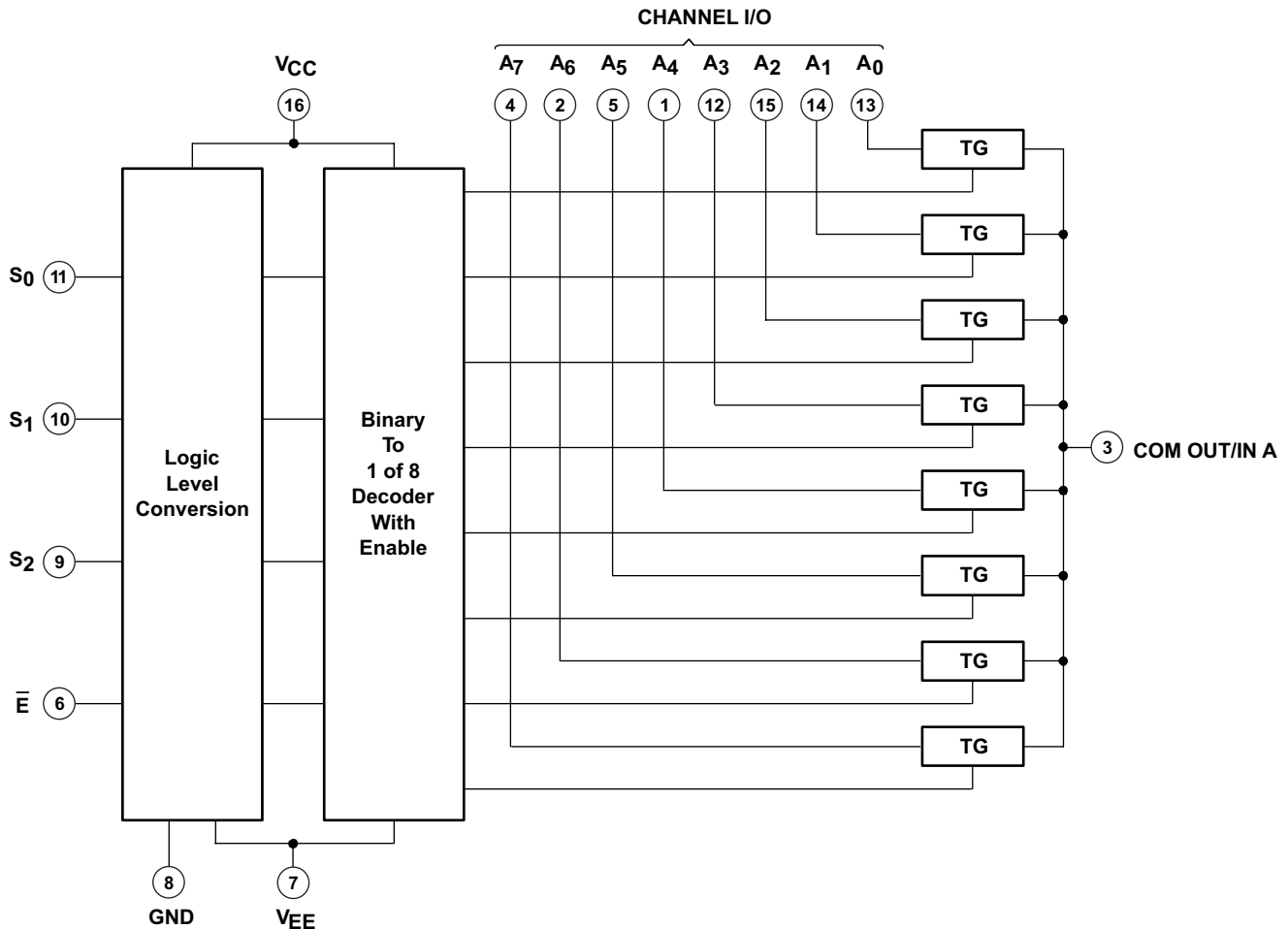
**Figure 9. Load Circuit and Voltage Waveforms**

## 8 Detailed Description

### 8.1 Overview

The CD74HC4051-EP is a digitally controlled analog switch that uses silicon gate CMOS technology to achieve operating speeds similar to LSTTL, with the low-power consumption of standard CMOS integrated circuits.

### 8.2 Functional Block Diagram



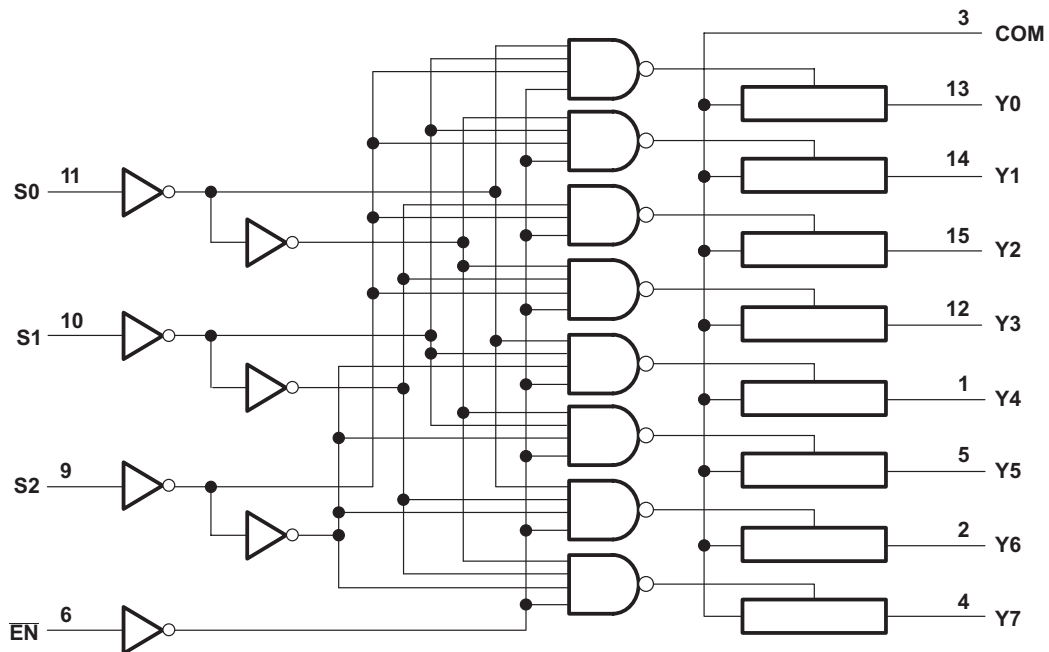
### 8.3 Feature Description

This analog multiplexer and demultiplexer controls analog voltages that may vary across the voltage supply range (that is,  $V_{CC}$  to  $V_{EE}$ ). These bidirectional switches allow the use of any analog input as an output and vice versa. The switches have low ON-resistance and low OFF leakages. In addition, the device has an enable control ( $E$ ) that, when high, disables all switches to their OFF state.

## 8.4 Device Functional Modes

**Table 1. Function Table**

INPUTS				ON CHANNEL (S)
	E	S2	S1	
L	L	L	L	A0
L	L	L	L	A1
L	L	L	H	A2
L	L	L	H	A3
L	L	H	L	A4
L	L	H	L	A5
L	L	H	H	A6
L	L	H	H	A7
H	X	X	X	None



**Figure 10. Logic Diagram (Positive Logic)**

## 9 Application and Implementation

### NOTE

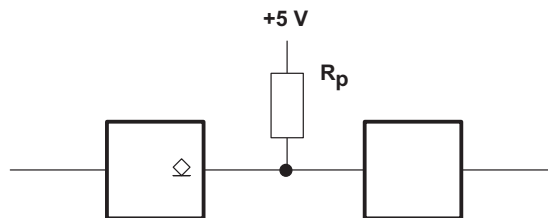
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

### 9.1 Application Information

#### 9.1.1 TTL-to-HC Interface

TTL output voltages and HC input voltages are incompatible, especially between the TTL high-level output voltage ( $V_{OH}$ ) and the HC high-level input voltage ( $V_{IH}$ ). This problem can be solved in two different ways. The first solution is to provide pullup resistors at the TTL outputs to ensure an adequate high-level TTL output voltage. A alternative method requires the use of level shifters.

### 9.2 Typical Application



**Figure 11. Typical Application Schematic TTL-to-HC Interface Using Open-Collector Output.**

#### 9.2.1 Design Requirements

Interfacing TTL open-collector outputs to HC-CMOS inputs requires design of pullup circuit balanced with drive capability to achieve timing and VOL-HC input specifications. Similar technique can be applied when using open-drain outputs.

#### 9.2.2 Detailed Design Procedure

Using pullup resistors to accommodate TTL output signals to interface with HC input circuits (see [Figure 11](#)), the design engineer must choose the resistance that is appropriate for the application. The minimum value of the resistor is determined by the maximum current  $I_{OL}$  that a TTL circuit can supply at the low-level output ( $V_{OL}$ ).

$$R_p \min = \frac{V_{CC} \max - V_{OL} \min}{I_{OL} + n \times I_{IL}}$$

where

- $n$  is the number of HC inputs to be driven
- $I_{IL}$  is their input current

(1)

$I_{IL}$ , having a value of only a few nanoamperes, is negligible in all calculations.

In the case of a SN74ALS03, [Equation 2](#) defines  $R_p \min$ :

$$R_p \min = \frac{5.5V - 0.4V}{8mA} = 640\Omega$$

(2)

To calculate the upper limit of this resistor, a sufficient  $V_{IH}$  high level must be ensured.

$$R_p \max = \frac{V_{CC} - V_{IH} \min}{n \times I_{IH}}$$

(3)

In this situation, the input current of HC devices is negligible and very high values also are obtained.

## Typical Application (continued)

When calculating the maximum allowable resistance, it is important to ensure that the maximum allowable rise time ( $t_r = 500$  ns) at the HC input is not exceeded. Equation 4 then applies:

$$V_{IH} = V_{CC}(1 - e^{\frac{-t}{R_p \times C}})$$

where

- C is the total load capacitance in the circuit (4)

C is composed of the output capacitance of the driving gate (approximately 10 pF), the total input capacitances of gates to be driven (approximately 5 pF each), and the line capacitance (approximately 1 pF/cm). The actual value is calculated by solving the equation for  $R_p$ :

$$R_p = \frac{-t}{C \times \ln(1 - \frac{3.5V}{5V})} \quad (5)$$

Assuming the total capacitance, C, is 30 pF, the maximum resistor is:

$$R_p = \frac{-500ns}{30pF \times \ln(1 - \frac{3.5V}{5V})} = 14k\Omega \quad (6)$$

Faster rise times result in lower impedance and more power consumption. The previous calculation is based on the assumption that the driving gate has an open collector. Conditions become more satisfactory, however, when a gate with totem-pole output (that is, SN74ALS00) is used. In that case, the gate output provides the voltage to be brought up to the value  $V_{OH} = 2.7$  V in less than 10 ns (the rise time of the TTL signal). The pullup resistor only has to pull the level to 3.5 V within the desired time. According to the previous formula, and with a required rise time of  $t_r = 50$  ns, the resistor is defined by Equation 7:

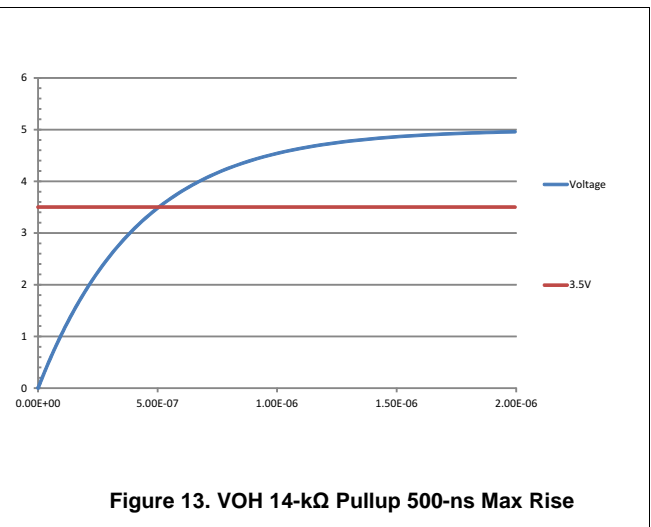
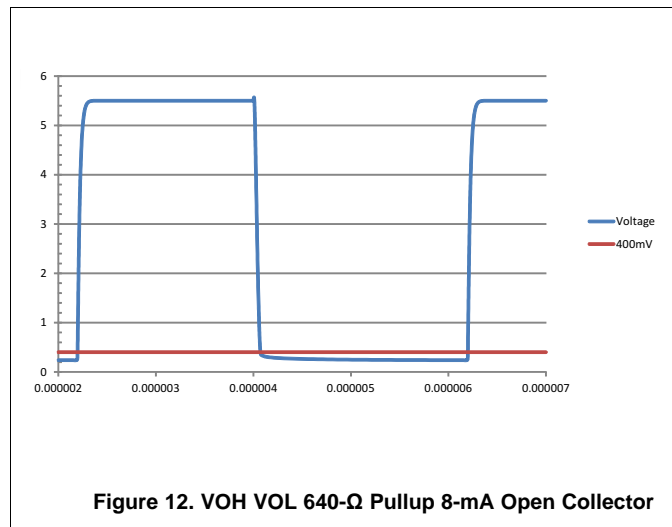
$$R_{p \text{ max}} = \frac{-50ns - 10ns}{30pF \times \ln(1 - \frac{3.5V - 2.7V}{5V - 2.7V})} = 3.12k\Omega \quad (7)$$

The upper limiting value of the resistor is primarily dictated by the rise time required. The larger the resistance, the longer the rise times and propagation delay times. Reducing the resistance increases speed and power dissipation.

The other method of accommodating TTL signals to HC circuits is accomplished with special level shifters. This solution is not recommended because the level shifter itself has no inherent logic functions and increases component and space requirements.

## Typical Application (continued)

### 9.2.3 Application Curves



## 10 Power Supply Recommendations

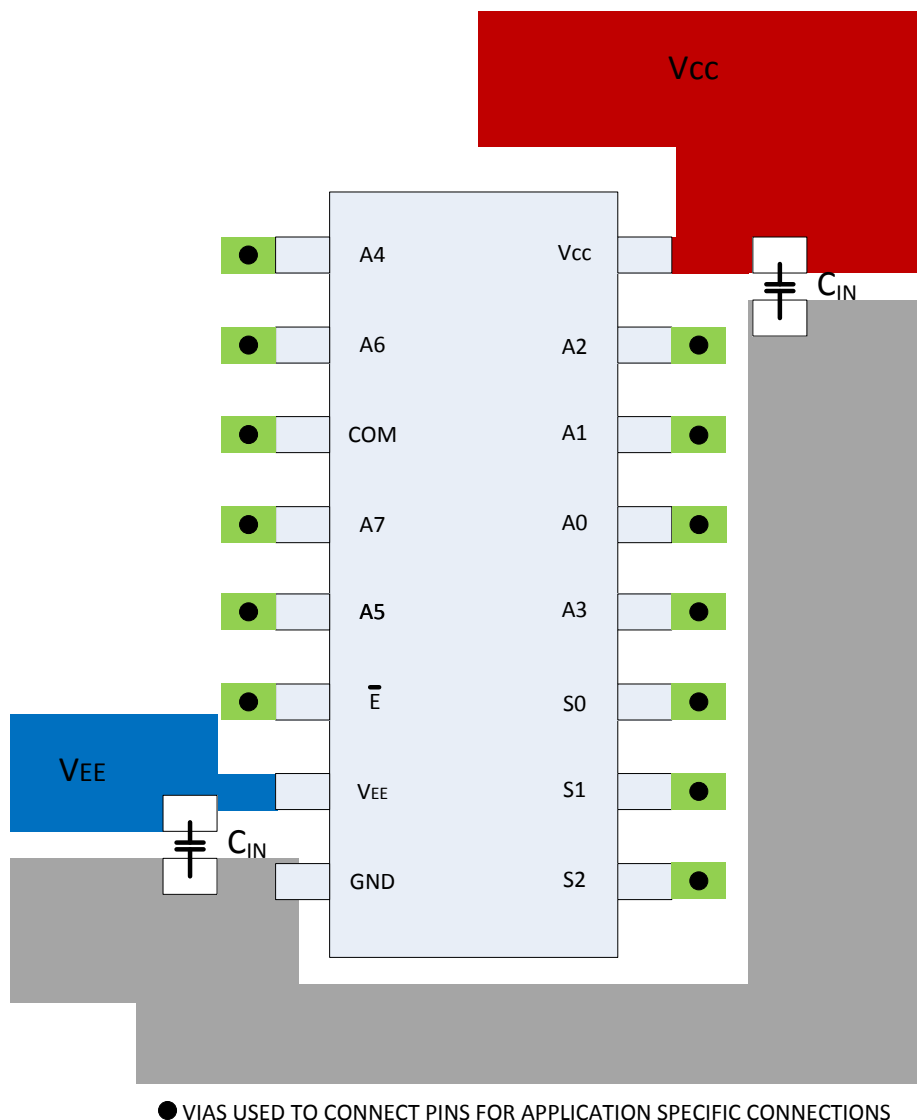
The threshold voltage of a CMOS circuit is determined by the geometry of the input transistors. These transistors are designed to sink the same input current at the required threshold voltage. The resulting voltage at the output is equivalent to 50% of the supply voltage  $V_{CC}$ . For an HC circuit, the channel width of the P-channel transistor of the input is approximately twice the value of an N-channel transistor. The purpose is to make both transistors have the same current characteristics, thus making the threshold voltage of their input at about 50% of the supply voltage  $V_{CC}$ .

## 11 Layout

### 11.1 Layout Guidelines

Analog channels inputs and outputs should be routed to optimize system requirements.  $V_{CC}$  and  $V_{EE}$  should have local decoupling capacitance placed close to device. Typical  $C_{in}$  values are 100 pF and 0.01  $\mu$ F per supply pin.

### 11.2 Layout Example



**Figure 14. Layout Example**

## 12 Device And Documentation Support

### 12.1 Trademarks

All trademarks are the property of their respective owners.

### 12.2 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

### 12.3 Glossary

[SLYZ022](#) — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

## 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



## PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package   Pins	Package qty   Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
<a href="#">CD74HC4051MM96EP</a>	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4051MEP
CD74HC4051MM96EP.A	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4051MEP
<a href="#">V62/03606-01XE</a>	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4051MEP

<sup>(1)</sup> **Status:** For more details on status, see our [product life cycle](#).

<sup>(2)</sup> **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

<sup>(4)</sup> **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

### OTHER QUALIFIED VERSIONS OF CD74HC4051-EP :

- Catalog : [CD74HC4051](#)

- Automotive : [CD74HC4051-Q1](#)

- Military : [CD54HC4051](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Military - QML certified for Military and Defense Applications

## TAPE AND REEL INFORMATION



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC4051MM96EP	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

## TAPE AND REEL BOX DIMENSIONS



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC4051MM96EP	SOIC	D	16	2500	353.0	353.0	32.0

D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- $\triangle C$  Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- $\triangle D$  Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.

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